



The European Network of Excellence
on RF MEMS and RF Microsystems



JOINT WORKSHOP ON MEMS RELIABILITY

When: at the ESREF conference, Oct. 2, 2006

Where: Wuppertal - Germany (ESREF 2006 location)

Organisation: ESREF, Dept. Elektronik TUW

Lehrstuhl für Elektronik
Bergische Universität Wuppertal



Objective: to enable the members from two European Networks of Excellence, PATENT and AMICOM, and the participants of the ESREF Conference to share know-how on MEMS Reliability issues.

Topics: The workshop studies all aspects of MEMS Reliability. Topics include but are not limited to: characterization methods, failure mechanisms, failure analysis, testing techniques and test structures, reliability techniques and methodology, design rules.

2nd CALL FOR PARTICIPATION

Contributors should submit electronically a short abstract (1 or 2 pages) including title and authors' affiliation, address and email. The abstract should reflect the significance of the contribution. Authors of accepted abstracts are willing to attend the workshop and perform a ~15-minute oral presentation, no final paper will be requested. The exact duration of the talks will depend on the final program. More details (timing) will follow later.

Please submit your contribution before **31th of July** to

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PATENT DfMM: The European Network of Excellence Patent-DfMM aims to establish a collaborative team to provide European industry with support in the field of "Design for Micro and Nano Manufacture (DfMM)" to ensure that problems affecting the manufacture and reliability of products based on micro nano technologies (MNT) can be addressed before prototype and pre-production.
(<http://www.patent-dfmm.org/>)

AMICOM: "AMICOM is a European Network of Excellence on RF MEMS and RF Microsystems Technology aiming to structure and consolidate the EU research in the field, by means of a comprehensive multidisciplinary approach (from design and modelling to testing and characterization through material and fabrication technology) spanning from fundamental science to actual implementation facilities. The final objective is to enhance the EU competitiveness in the field of advanced integrated circuit and packaging technologies for microwave, and millimeter-wave applications by supporting the industrial stakeholders (<http://www.amicom.info>).

ESREF 2006 : is the 17th European Symposium on Reliability of Electron Devices. This international symposium continues to focus on recent developments and future directions in Quality and Reliability Management of materials, devices and circuits for micro-, nano-, and optoelectronics. It provides a European forum for developing all aspects of reliability management and innovative analysis techniques for present and future electronic applications. (<http://www.esref.org>)